

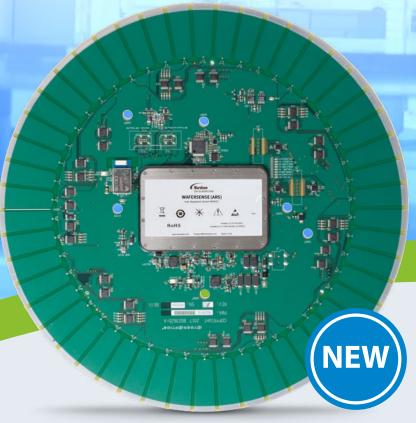




Save Time

Save Expense Improve Yields

Semiconductor fabs and OEMs worldwide value the accuracy, precision and versatility of the WaferSense ARS - The most efficient and effective wireless measurement device for resistance.





WaferSense®

Auto Resistance Sensor™ (ARS)

Metrology Sensors

Real time resistance measurement of plating cell contacts.

Quickly monitors and identifies resistance measurements with 50 separate measurement pads around the perimeter, utilizing the Kelvin Sensing (4-wire resistance) method for accurate measurement of low value resistance.



WaferSense® Auto Resistance Sensor™ (ARS)

Shorten Maintenance Cycles

Shorten equipment maintenance cycles with

- Collect and monitor real time measurement of contact resistance plating cells to detect residue affecting plating pins.
- Thinner wafer-like form factor allows ARS to be handled like any other wafer in the tool.
- Save time and costs associated with metrology wafer measurements.

Predict Tool Maintenance

With quantitative analysis of measured mean resistance over time.

- Optimize preventative maintenance plans with accurate, repeatable data trends.
- Record data to enable comparisons between

Specifications	
Form factor	Available in 300mm
Part number	8030138
Software	CyberSpectrum
Operating range	0.1 m Ω to 200 m Ω , 1Ω to 10Ω
Accuracy	$1m\Omega\pm1\%$ of range with normalized readings. Resolution of $100\mu\Omega$
Housing material	Edge contacts are mechanically robust with noble metal plating 50 Measurement Pads. Chemically compatible with SABRE* chemistry and cleaning procedures
Operating temperature	20°C to 60°C
Weight	270 g and 5.5mm thick
Battery-duration	>3 hours per charge. Inductive wireless charging and hands free operation
Communication	Bluetooth, Class 1, 2.4 GHz
Operating system	Windows 10
Product components	Resistance measurement device, charging clean case, carrying suitcase, USB communications link module, power adapter and application software
Calibration	Factory recalibration recommended annually

^{*}SABRE is a registered trademark of Lam Research Corporation

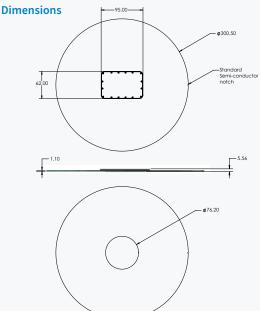
past and present, as well as one tool to another with new CyberSpectrum™ software.

- Establish and save a baseline from a known clean and new contact ring.
- Compare mean resistances to baseline values and receive early warnings for nonuniform deposition associated with changes to plating pins.

Improve Cell-to-cell Process Uniformity

With objective and repeatable resistance measurement.

- Predict when plating fingers have to be serviced using measured mean resistances.
- Increase yield across various plating cells in the tool by detecting the increase in contact resistance in real time.



For more information. speak with your Nordson representative or contact your Nordson regional office

Nordson Test & Inspection Europe, SEA, Africa

ti-sales-eu@nordson.com

Nordson Test & Inspection **Americas**

ti-sales-us@nordson.com

Nordson Test & Inspection China

ti-sales-cn@nordson.com

Nordson Test & Inspection Japan

ti-sales-jp@nordson.com

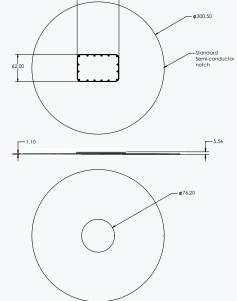
Nordson Test & Inspection Singapore

ti-sales-eu@nordson.com

Nordson Test & Inspection

ti-sales-tw@nordson.com

Nordson Test & Inspection Korea ti-sales-korea@nordson.com



Real-time data

CyberSpectrum™ Software included

Displays real-time numerical and graphical data with mean and individual resistance measurements. Replays log file data for various sessions for review and analysis.

Records data in a .csv format by appending data from each session with time stamped entry.

